

# New (TH)GEM coating materials characterised using spectroscopy methods

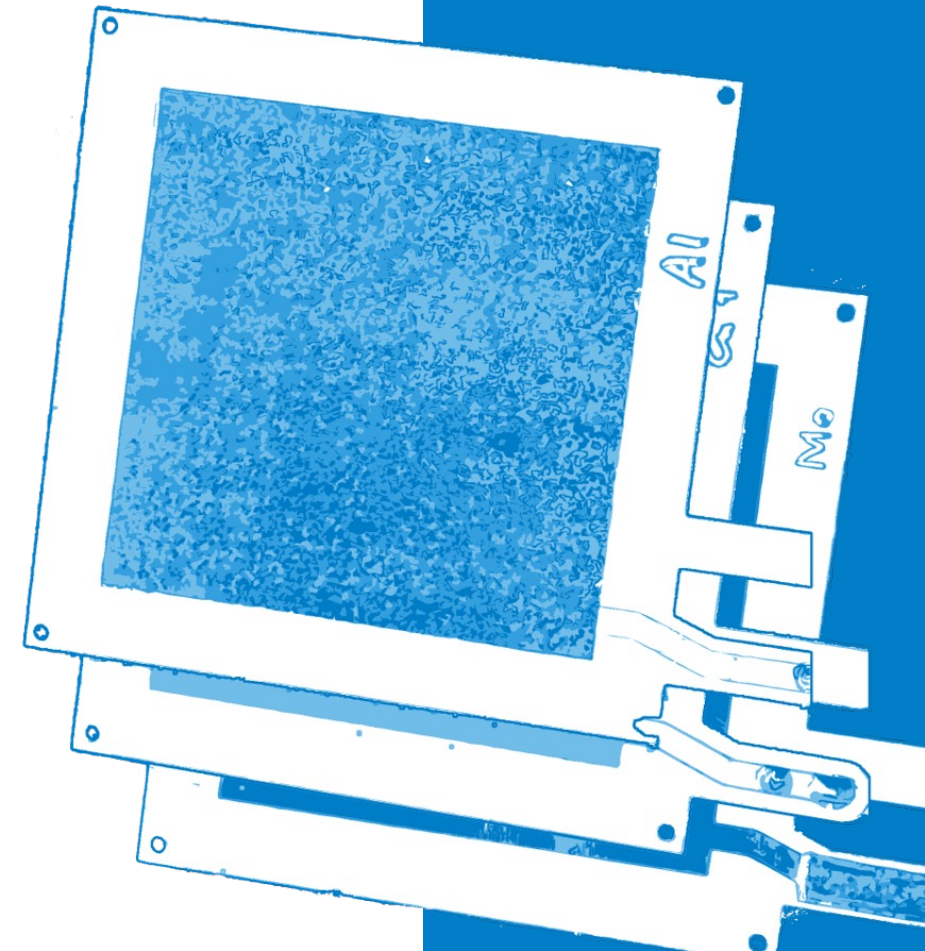
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Laura Fabbietti<sup>1</sup>, Tobias Waldmann<sup>1</sup>, Lukas Lautner<sup>1</sup>

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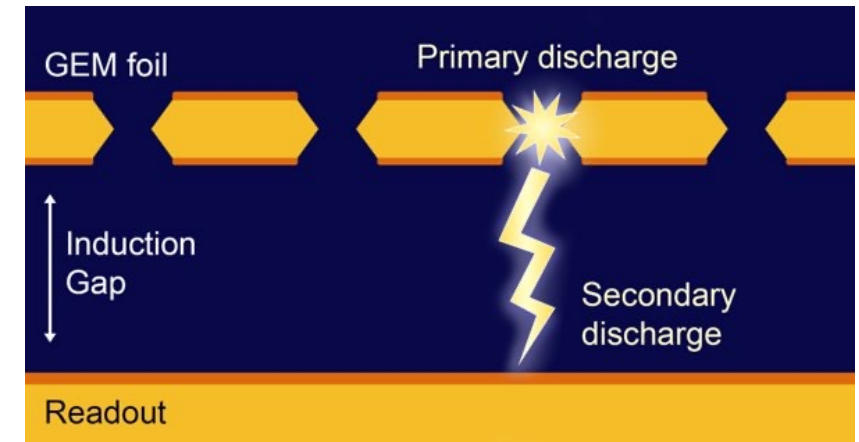
Micro Pattern Gaseous Detectors 2022

15th December 2022, Weizmann Institute of Science, Rehovot, Israel

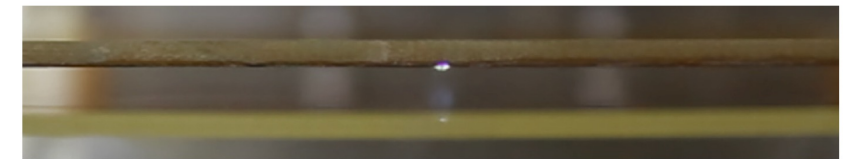


# Discharges in (TH)GEMs

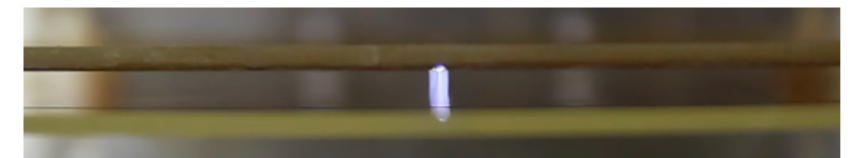
- GEM discharges (sparks) have been widely studied
- There are different types of GEM discharges
  - **Primary discharges** occur inside GEM hole and are most prominent
  - **Secondary discharges** occur in the gap between GEM and anode and are more dangerous
- Methods have been developed to mitigate them during operation
  - RC components, gas, foil properties, etc.
    - [S. Bachmann et al. NIM A 479 \(2002\) 294-308](#)
    - [P. Gasik et al. NIM A 870 \(2017\) 116](#)
    - [A. Deisting et al. NIM A 937 \(2019\) 168-180](#)
    - [L. Lautner et al. JINST 14 \(2019\) P08024](#)
    - ...



Types of discharges in (TH)GEM detectors



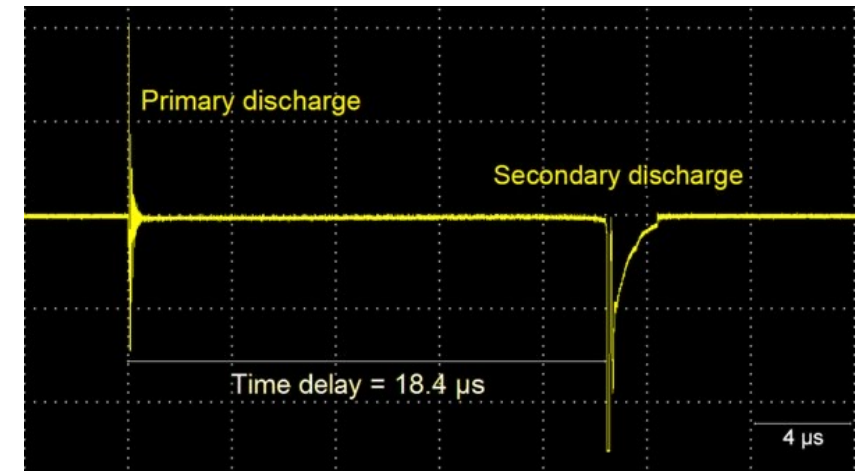
Primary discharge in a GEM hole



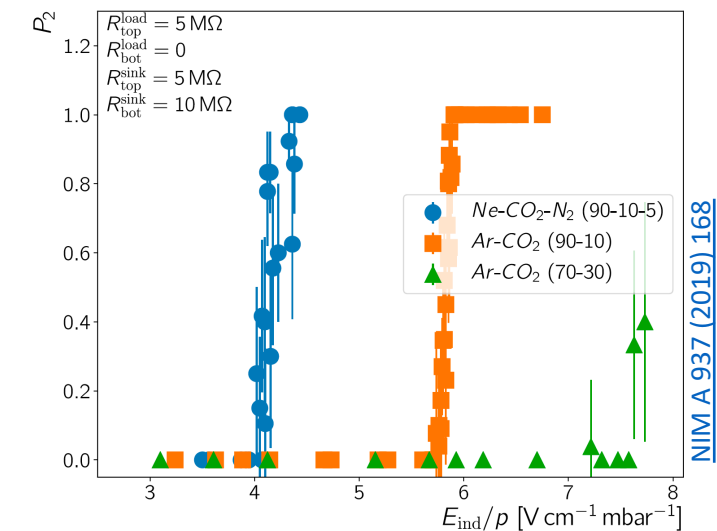
Secondary discharge between GEM and anode

# Secondary discharges in (TH)GEMs

- Time delay in the order of  $\mu\text{s}$  between primary and secondary discharge
- Steep onset of secondary discharge probability vs  $E_{\text{ind}}$  below amplification values
- However, there are remaining questions especially concerning their formation mechanisms
  - Thermal processes considered as main mechanism of secondary electron emission
    - [A. Deisting et al. NIM A 937 \(2019\) 168-180](#)
    - [A. Utrobicic et al. NIM A 940 \(2019\) 262-273](#)



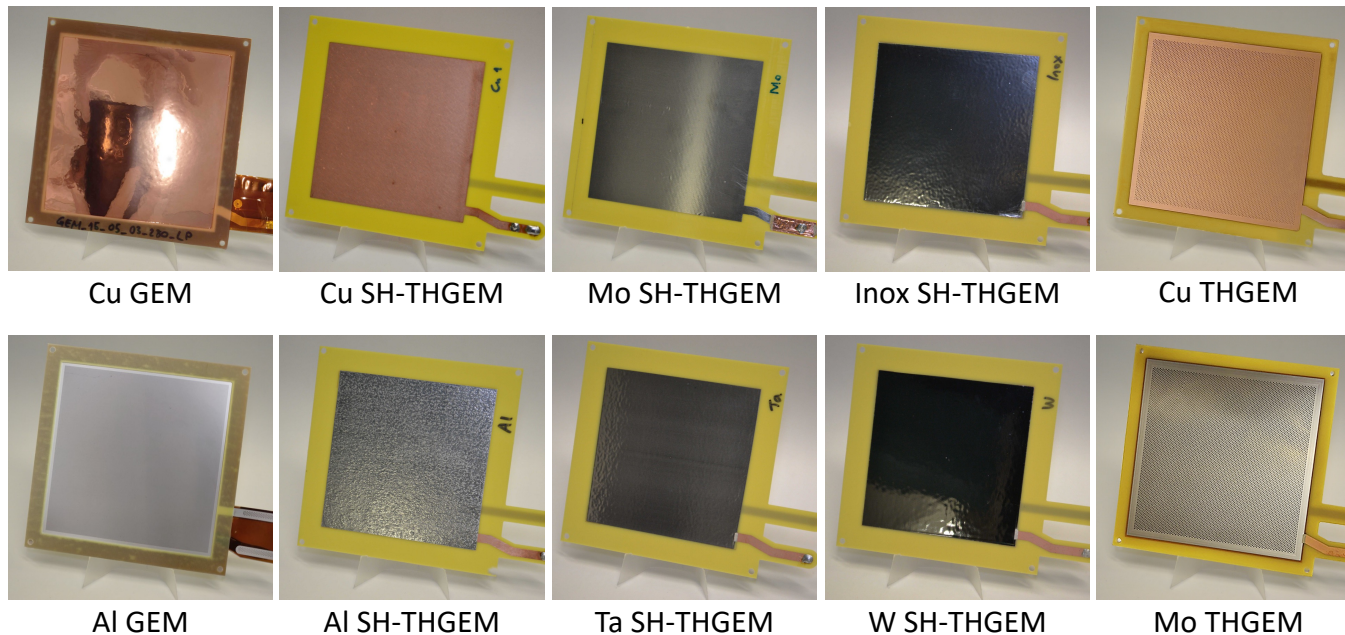
Signals induced by discharges on the readout electrode



Secondary discharge probability of GEMs vs  $E_{\text{ind}}$

# (TH)GEMs with different coating materials

- So far there are not many systematic studies investigating the effects of material choice in (TH)GEMs on various performance criteria
  - Conductive top and bottom electrode layers are typically made of copper
- GEMs, THGEMs and SH-THGEMs (single hole) with various cladding materials were produced and studied
  - Results from the SH-THGEMs summarized in [B. Ulukutlu et al. NIM A 1019 \(2021\) 165829](#)

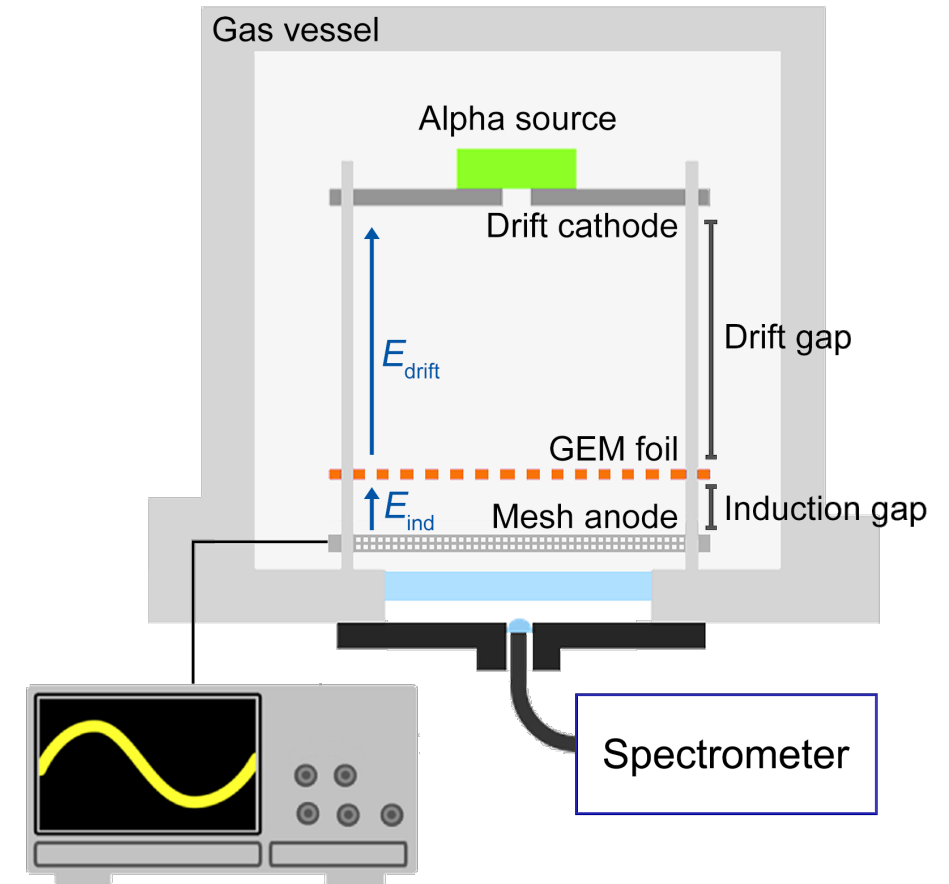


	Conductivity [10 <sup>6</sup> S/m]	Work function [eV]	Melting point [°C]	Boiling point [°C]	Thermal conductivity [W/m*K]	Density [g/cm <sup>3</sup> ]
Al	36.9	4.08	660	2470	237	2.702
W	8.9	4.5	3422	5550	174	19.35
Cu	58.7	4.7	1083	2575	386	8.96
Inox	1.37	4.4	1510	2750*	16.3	7.85
Ta	7.6	4.22	3017	5365	57.5	16.65
Mo	18.7	4.5	2623	4651	138	10.22

\*for Fe

# Experimental setup

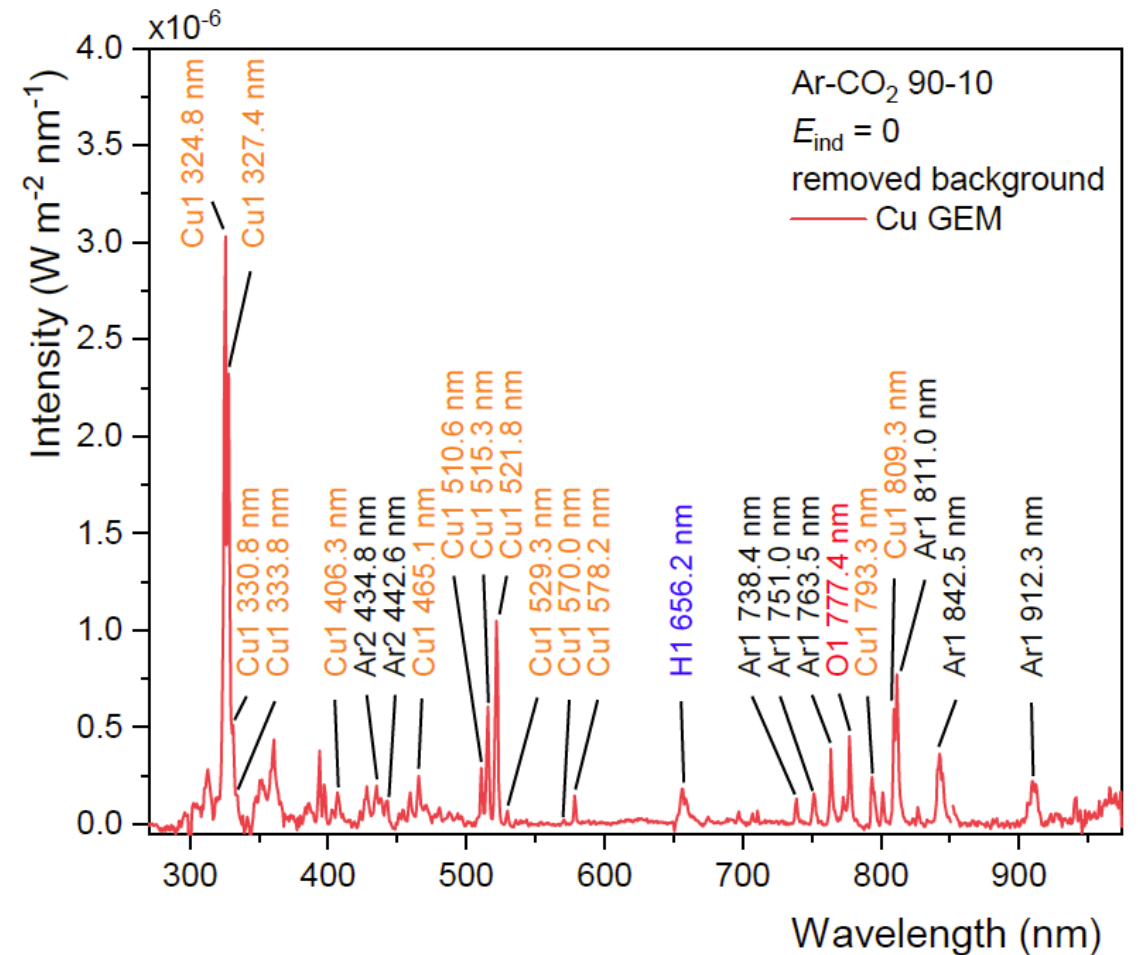
- GEM detector
  - Mixed alpha source ( $^{239}\text{Pu}+^{241}\text{Am}+^{244}\text{Cm}$ )
  - Gas mixture: Ar-CO<sub>2</sub> 90-10
  - Drift gap = 27 mm, drift field = 400 V/cm
  - Induction gap = 2 mm
- Discharges are counted/identified with an oscilloscope via the electrical signal they induce on the readout electrode
- Light emitted from discharges is studied with spectroscopy methods
  - A transparent mesh anode and a window is used
  - Light is collected with a collimating lens
  - Emission spectrum is analysed with Ocean Optics QE65000 (UV-VIS-NIR) spectrometer



Schematic of the used detector setup

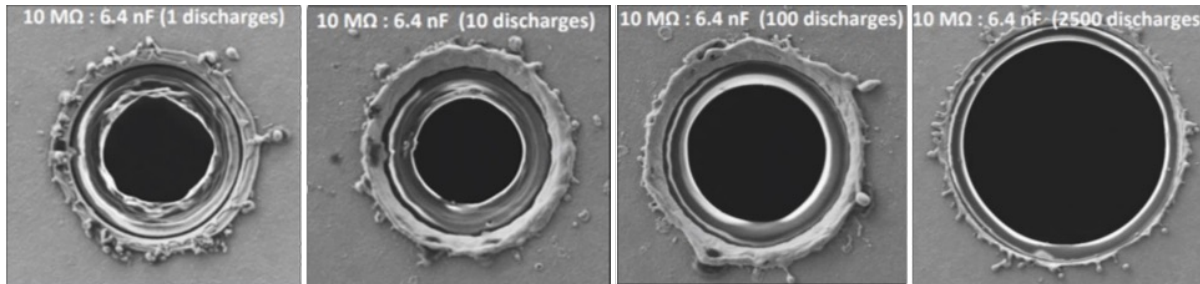
# Spectra of primary GEM discharges

- Measuring emission spectra of the light emitted during primary discharges
- Calibrated spectrometer and removed background
- Identifying emission lines via peak fitting and comparing to spectroscopy database
- Longer wavelength regions dominated by the emission lines from the used gas mixture (e.g. Ar-CO<sub>2</sub>)

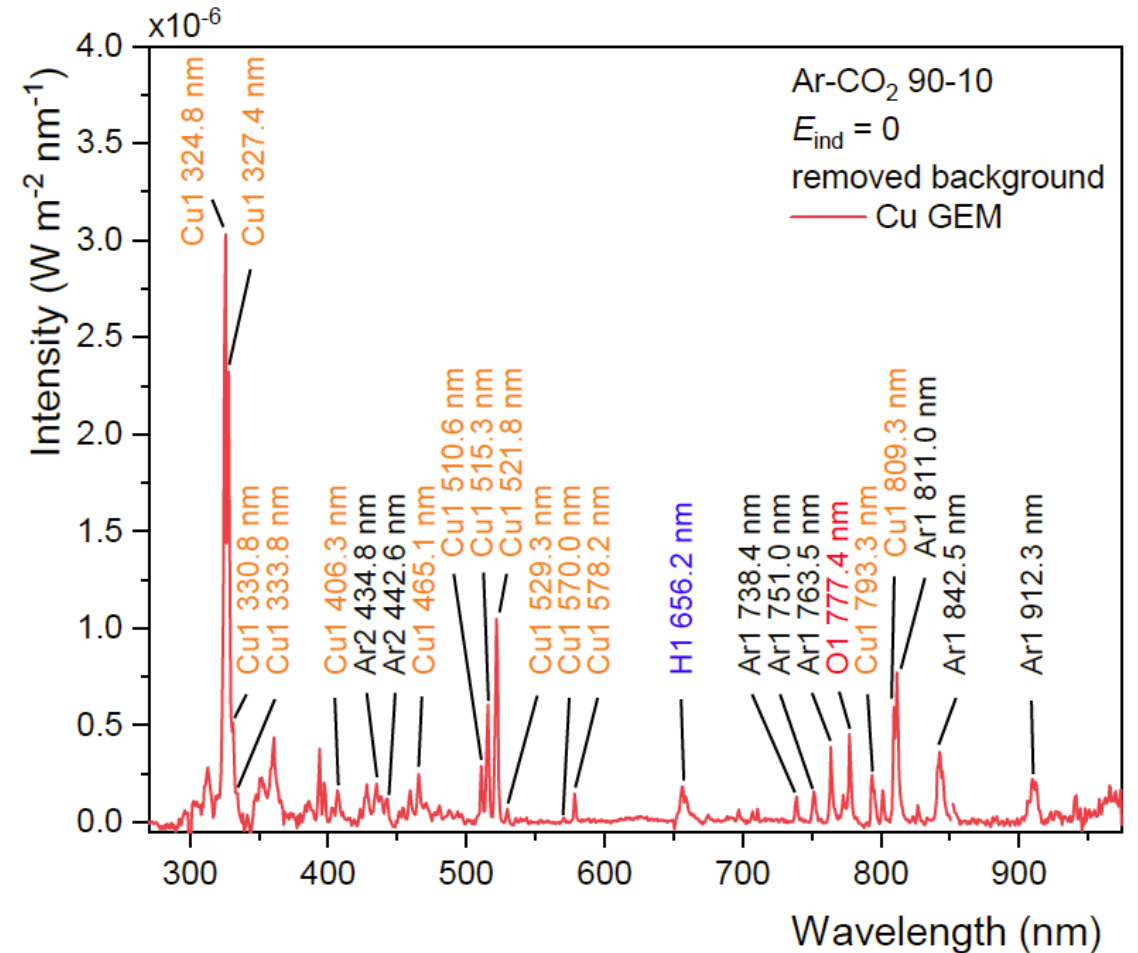


# Spectra of primary GEM discharges

- Copper emission lines observed!
  - Presence of foil cladding material in the hot discharge plasma
  - Vaporization of the copper layer
  - Can be observed indirectly via the damage caused by discharges

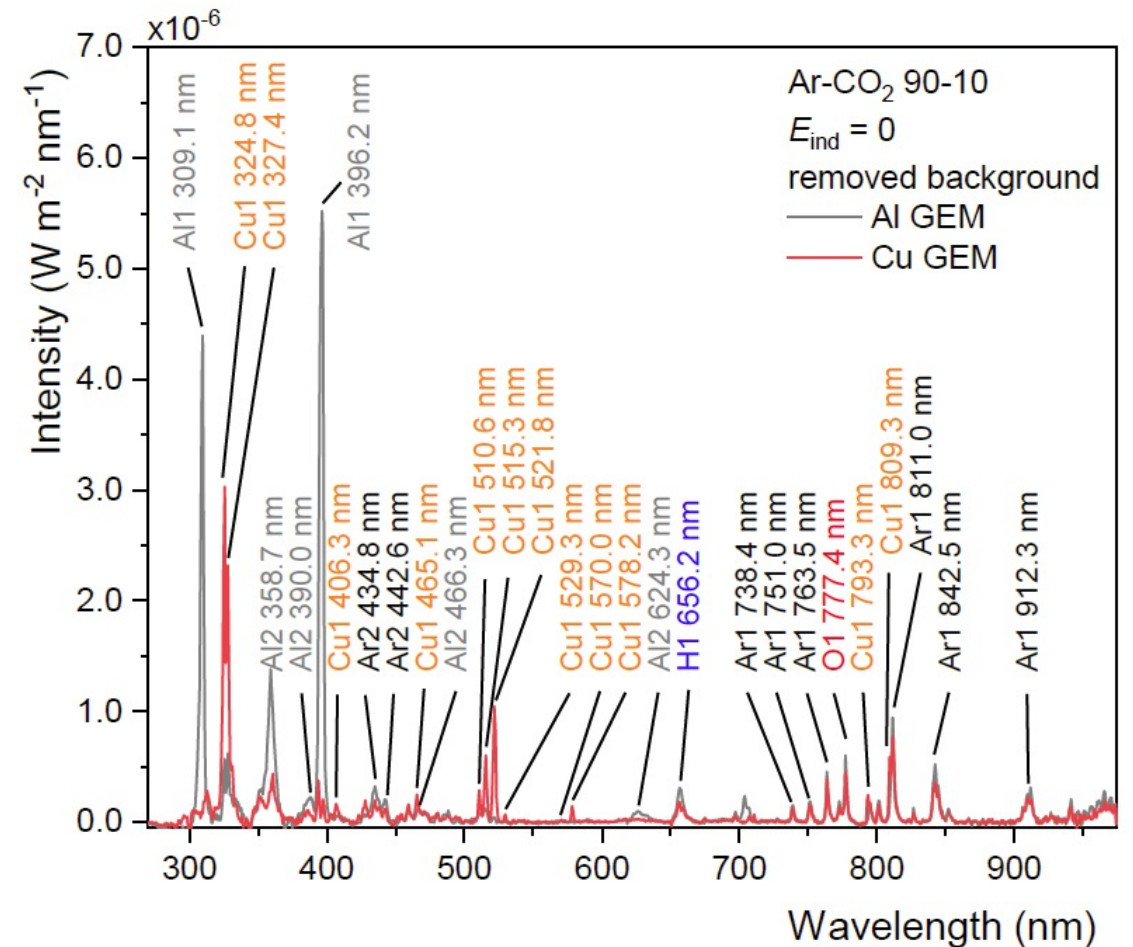


Effects of discharges on a GEM hole [[J.A. Merlin, RD51 Collaboration Meeting 2018](#)]



# Comparing different GEM materials

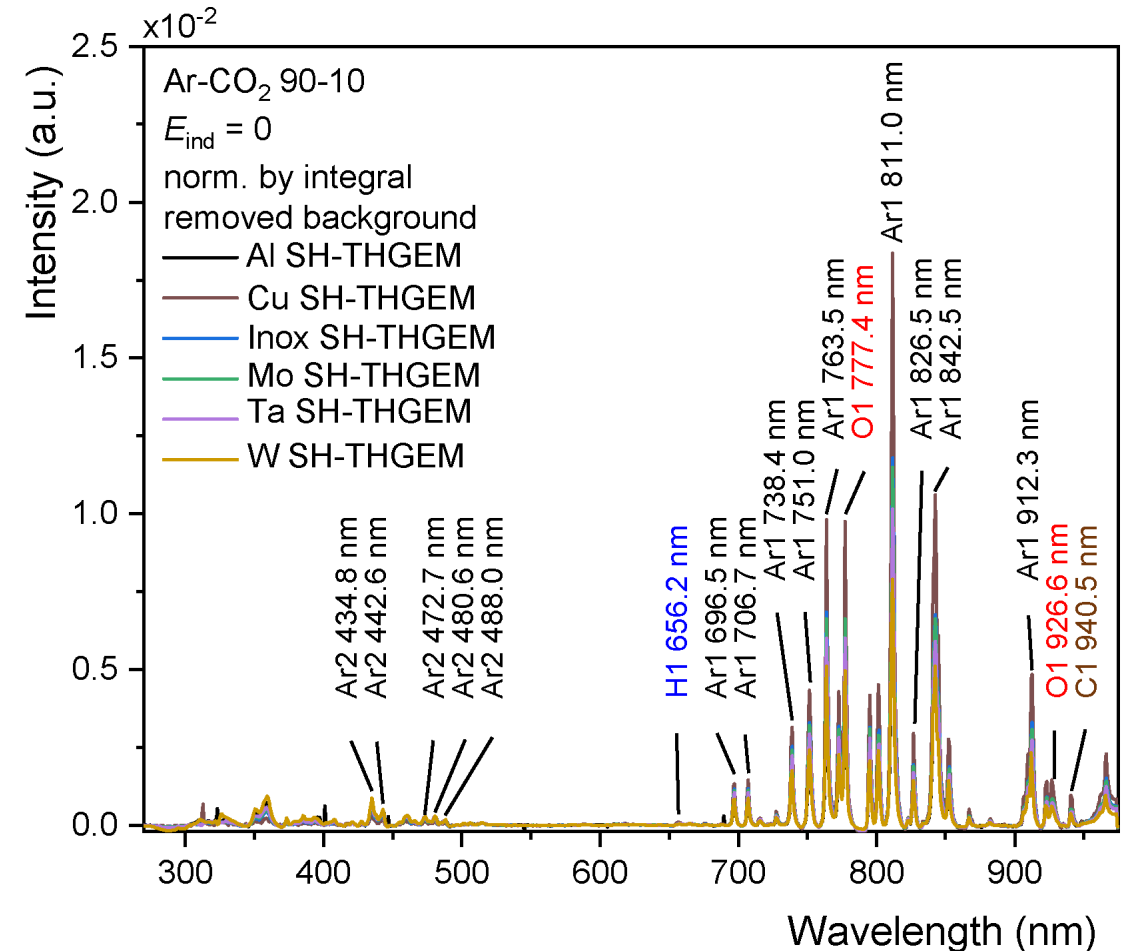
- Comparison with aluminium GEM
  - Aluminium emission lines observed
  - Comparable intensity of peaks from the excitation of the used gas
- Further confirmation of the presence of foil material in discharge plasma
- Correct identification of the emission lines





# Comparing different THGEM materials

- Using single-hole THGEMs for improved consistency in measured light from the constrained discharge location
- Very similar emission spectra in all SH-THGEMs
  - Spectra dominated by the gas emission lines
  - None of the used THGEMs lead to emission lines corresponding to foil cladding material
- Reduced material vaporization from discharges in THGEM hole geometry
  - Better heat dissipation due to thicker cladding material and larger area
- Secondary discharges still prevalent in THGEMs
  - No direct connection between material vaporization and secondary discharge formation



# Stability against primary discharges

- Primary discharges occur at very similar applied fields regardless of material
  - Streamer mechanism does not depend on the cathode material
  - Charge density as the driving factor for primary discharge formation
    - Critical charge limit shown to be dictated by the used gas mixture and field geometry inside hole [[NIM A 870 \(2017\) 116](#)]
- No material dependence expected and none observed!

## Onset of primary discharge formation

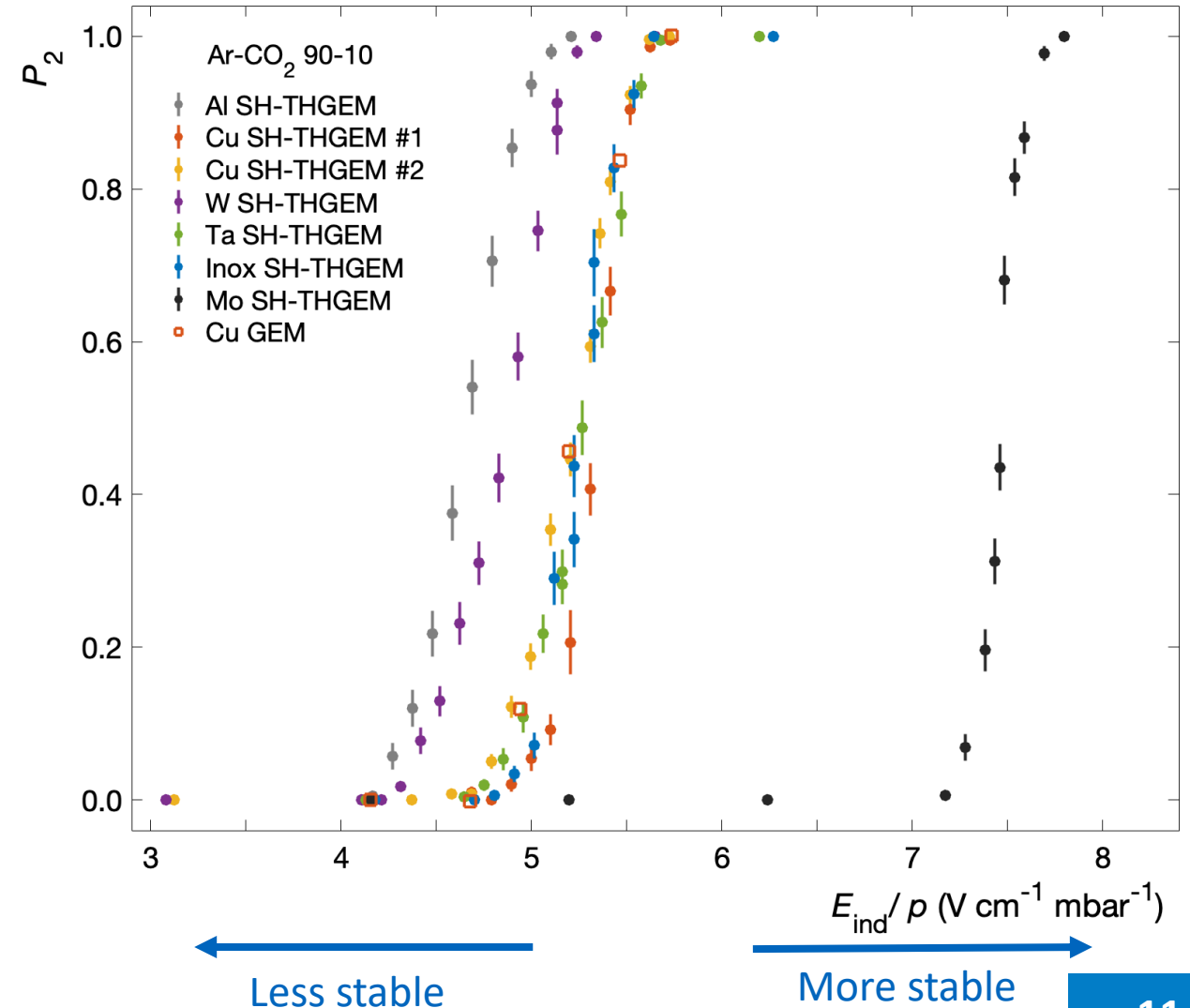
THGEM cladding material	Applied voltage across foil [V]
Copper	1680
Aluminium	1690
Molybdenum	1700
Stainless steel	1685
Tantalum	1700
Tungsten	1683

# Secondary discharge stability

- Secondary discharge probability:

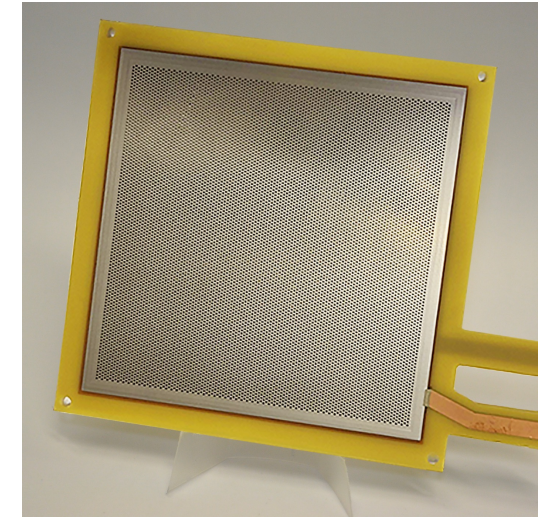
$$P_2 = \frac{N_{\text{Secondary Discharge}}}{N_{\text{Primary Discharge}}}$$

- Data for Cu GEM from [NIM A 937 \(2019\) 168](#)
- **Molybdenum SH-THGEM** displays especially high stability
  - Is this due to the material properties?
  - The observed hierarchy cannot be explained by any of the material properties expected to be relevant for discharge formation
  - Surface quality?

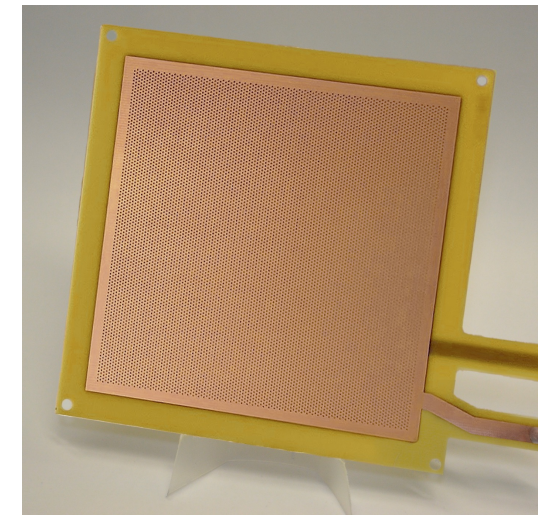


# Multi-hole Mo-THGEM

- Further investigations on Mo stability
- First, full-scale Mo-THGEM produced at the CERN MPT lab
  - 25  $\mu\text{m}$  thick molybdenum foil glued on the fiberglass PCB material
- Cu multi-hole THGEM for reference
- Same dimensions and tools used for production
- Special surface treatment to ensure smoothness
  - Polishing and cleaning



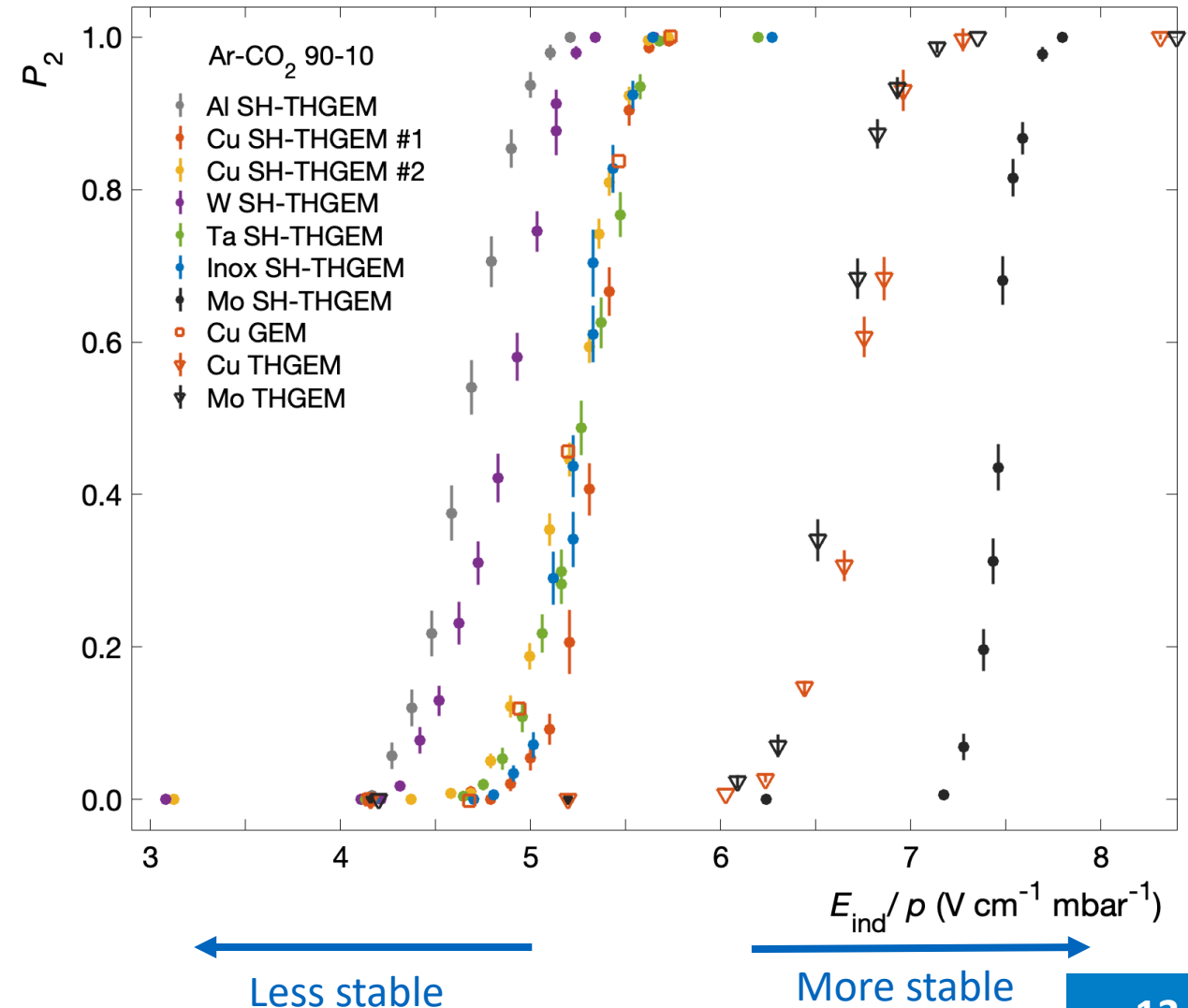
Mo THGEM



Cu THGEM

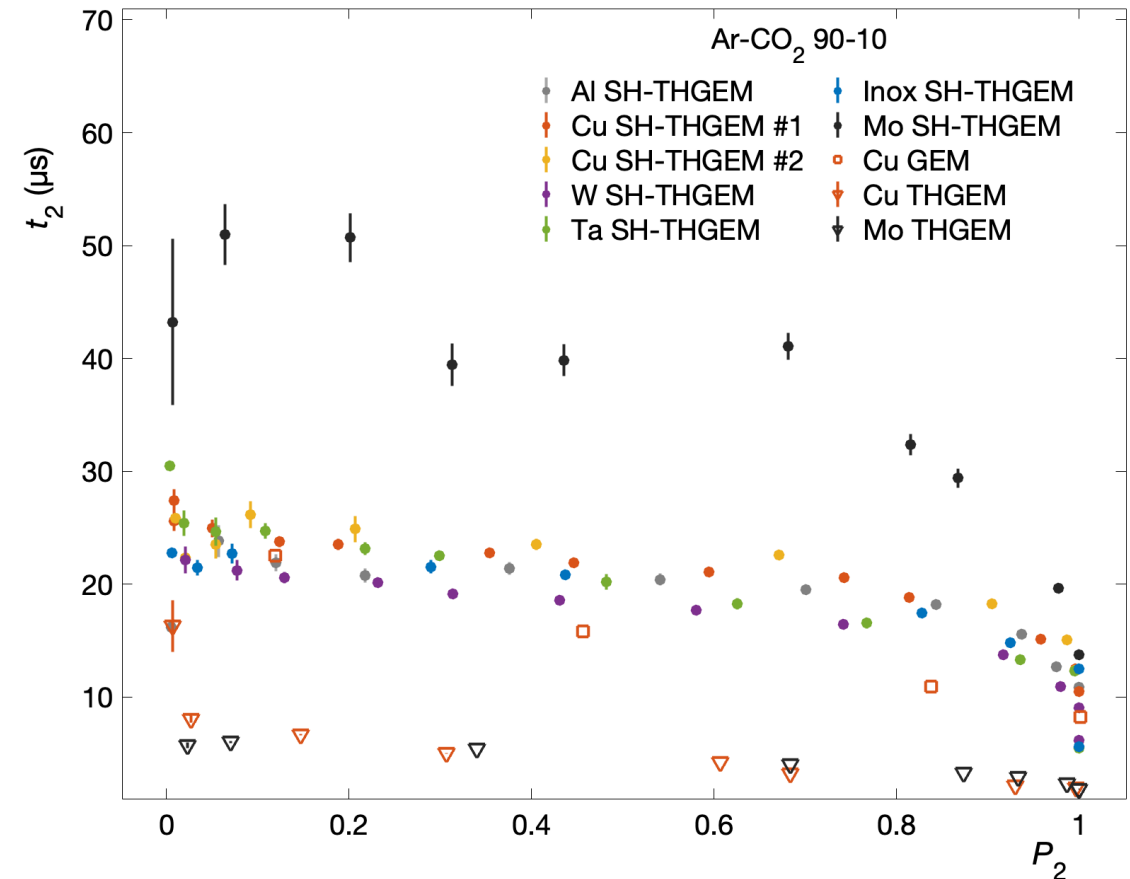
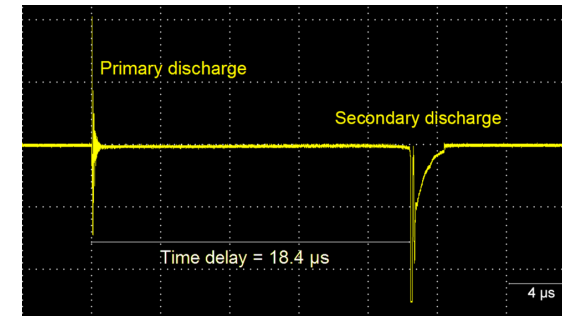
# Secondary discharge stability

- Both multi-hole THGEM samples are stable against secondary discharges compared to previous results from:
  - [A. Deisting et al. NIM A 937 \(2019\) 168-180](#)
  - [A. Utrobicic et al. NIM A 940 \(2019\) 262-273](#)
- The enhanced stability of molybdenum not replicated with the multi-hole Mo THGEM
  - Polished Cu THGEM is equally stable
- Effect of surface properties more than material properties?
  - Flipping THGEMs (vs. drilling direction) observed to make no difference



# Time delay

- Duration between the primary and secondary discharges
- Most of the SH-THGEMs are consistent with previous observations with GEMs
- Molybdenum SH-THGEM is again an outlier
- Both tested multi-hole THGEMs lead to quicker secondary discharges



# Conclusion and outlook

1. Spectroscopy offers a new perspective on GEM discharge studies
  - a. Vaporization of foil material observed for GEM foils
  - b. Vaporization rate significantly reduced with THGEMs → better heat dissipation
2. Significant variance in secondary discharge stability observed between samples
  - a. Not easily explained by material properties and could be related to oxide layers or quality of the hole edges
  - b. Surface quality of the structure could be the key
3. Further visual studies with multi-hole THGEMs to rule out local hotspots
  - a. Microscope imaging of the THGEM holes surfaces

Nuclear Inst. and Methods in Physics Research, A 1019 (2021) 165829



New (TH)GEM coating materials characterized using spectroscopy methods

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# Thank you for your attention!

Any questions?

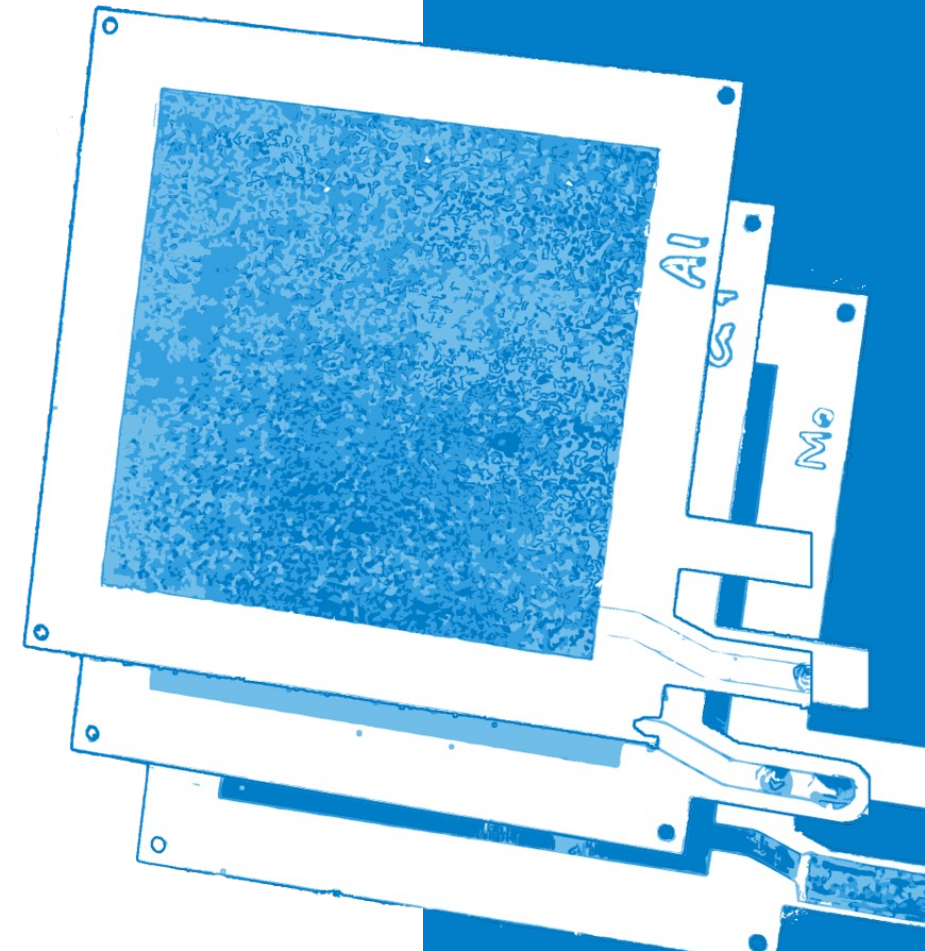
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Sachbeihilfe: „Eine umfassende Untersuchung  
der Entladungserzeugungsmechanismen in Micro-  
Pattern Gas Detektoren“

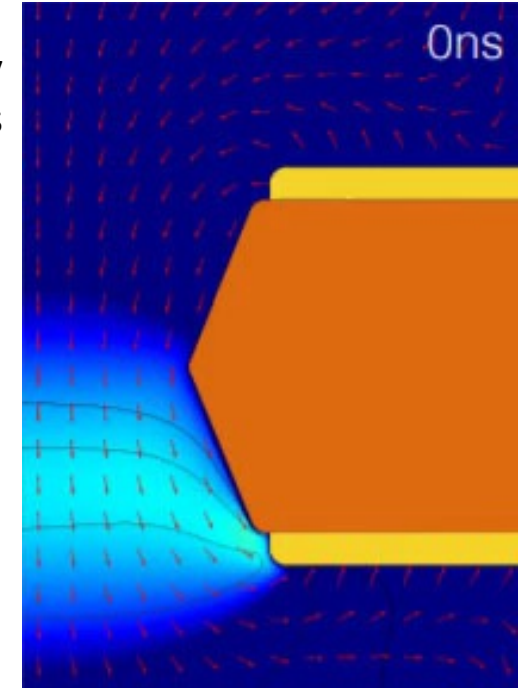




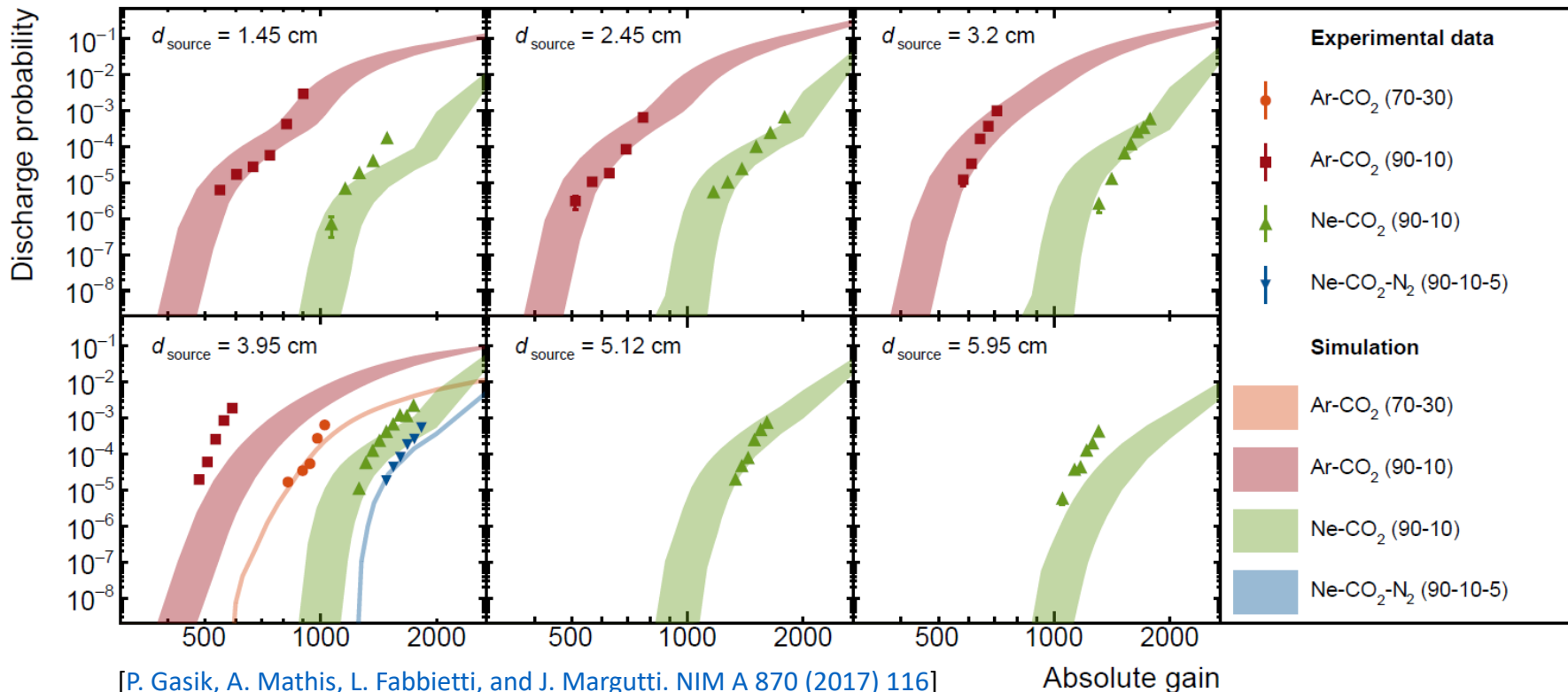
# Formation of primary discharges

- Charge density as the driving factor for primary discharge formation
  - Primary discharge occurs when a critical number of charge carriers is exceeded within the hole

Streamer development in GEM hole leading to primary discharges



Standard GEM

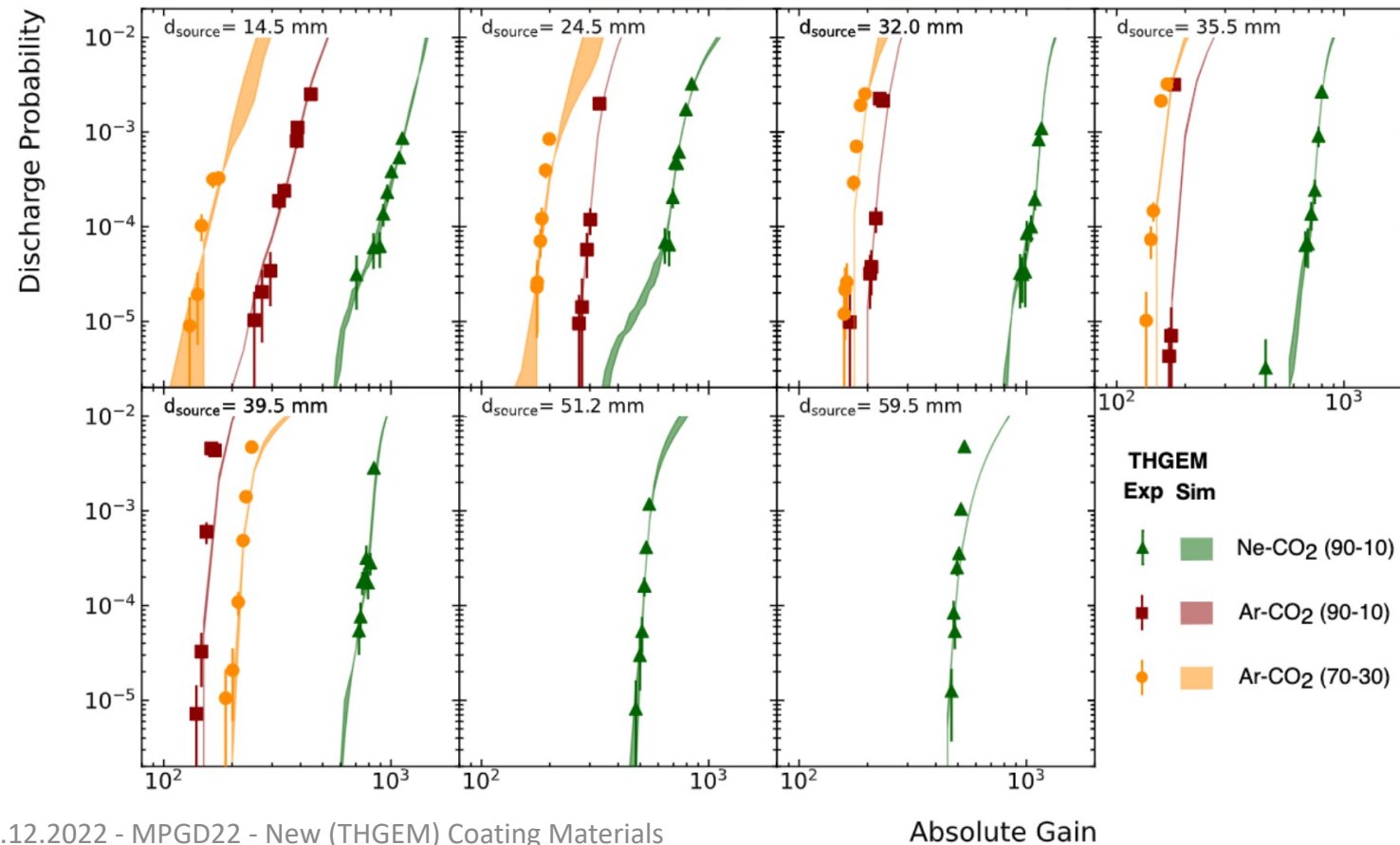


[P. Gasik, A. Mathis, L. Fabbietti, and J. Margutti. NIM A 870 (2017) 116]

Gas	$Q_{crit}$
Ar-CO <sub>2</sub> (90-10)	$(4.7 \pm 0.6) \times 10^6$
Ne-CO <sub>2</sub> (90-10)	$(7.3 \pm 0.9) \times 10^6$

# Primary discharge limits for THGEMs

- This theory was also shown to explain the observed reduced primary discharge stability of THGEMs



## 11.2x 11.2 cm<sup>2</sup> THGEM

Gas	THGEM		GEM	
	$\langle Q_{crit} \rangle$ [ $\times 10^6 e$ ]	$t_{int}$ [ns]	$Q_{crit}$ [ $\times 10^6 e$ ]	$t_{int}$ [ns]
Ne-CO <sub>2</sub> (90-10)	$7.1 \pm 2.2$	30–210	$7.3 \pm 0.9$	20–90
Ar-CO <sub>2</sub> (90-10)	$4.3 \pm 1.5$	20–110	$4.7 \pm 0.6$	15–50
Ar-CO <sub>2</sub> (70-30)	$2.5 \pm 0.9$	40–310	–	–

[P.Gasik, L.Lautner et al. NIM A  
1047 (2022) 167730]

**See also talk from  
P. Gasik tomorrow!**

# Delayed secondary discharges

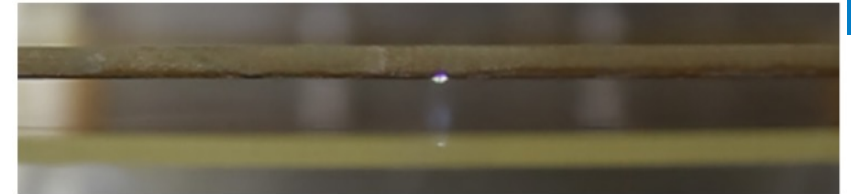
More dangerous discharge in the transfer/induction gap appearing  $\mu\text{s}$  after the primary spark

- Mitigation strategies established
  - ❑ L. Lautner, et al. JINST 14 (2019) no.08, P08024
  - ❑ A. Deisting, et al. NIM A 937 (2019) 168-180

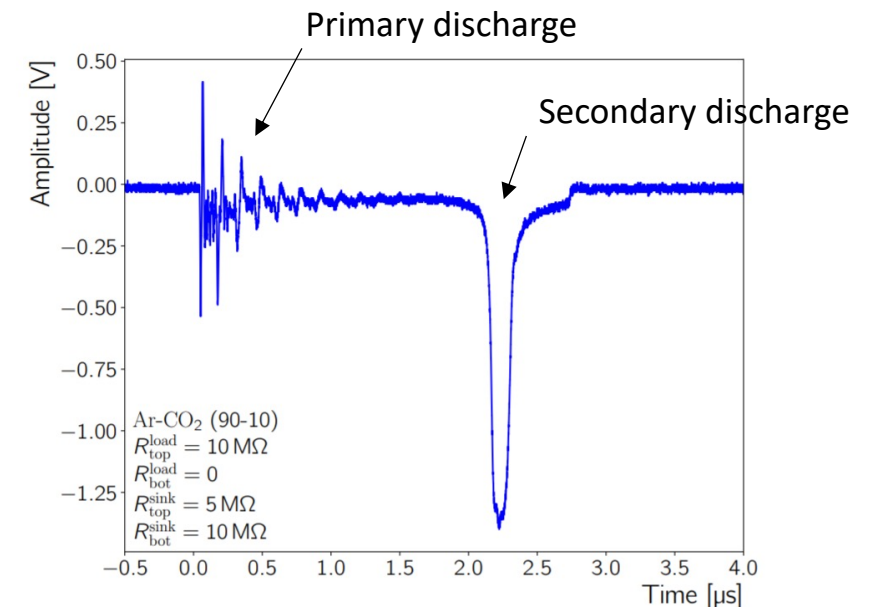
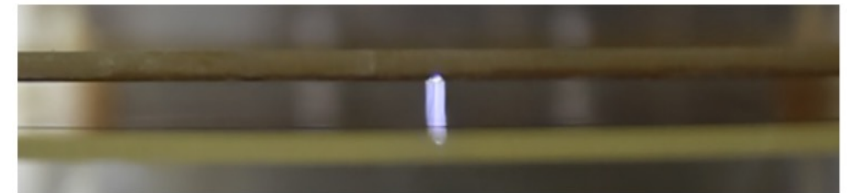
For discharges to occur a source of electrons is needed. This source is not fully understood for delayed secondary discharges.

- Leading theory: Heating of the cathode after the primary discharge
  - ❑ A. Deisting, et al. NIM A 937 (2019) 168-180
  - ❑ A. Utrobicic, et al. NIM A 940 (2019) 262-273

a) Primary discharge



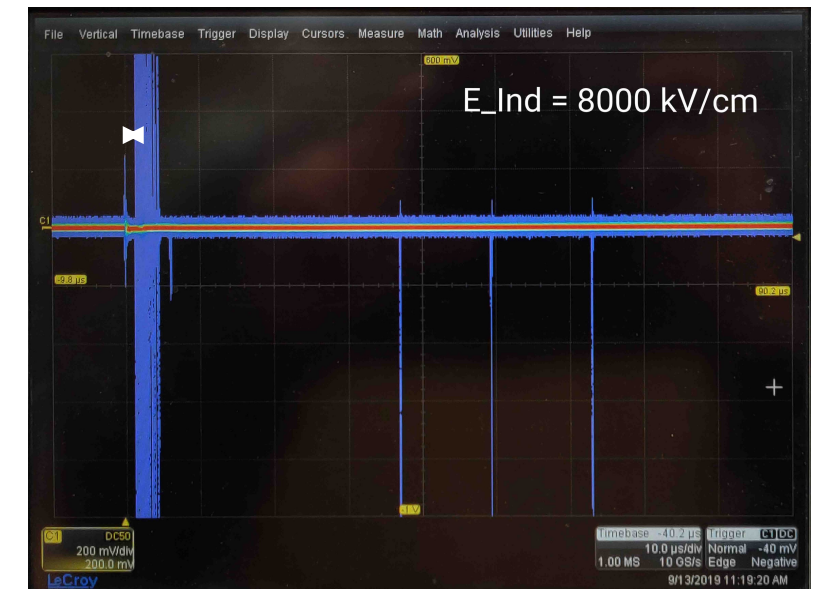
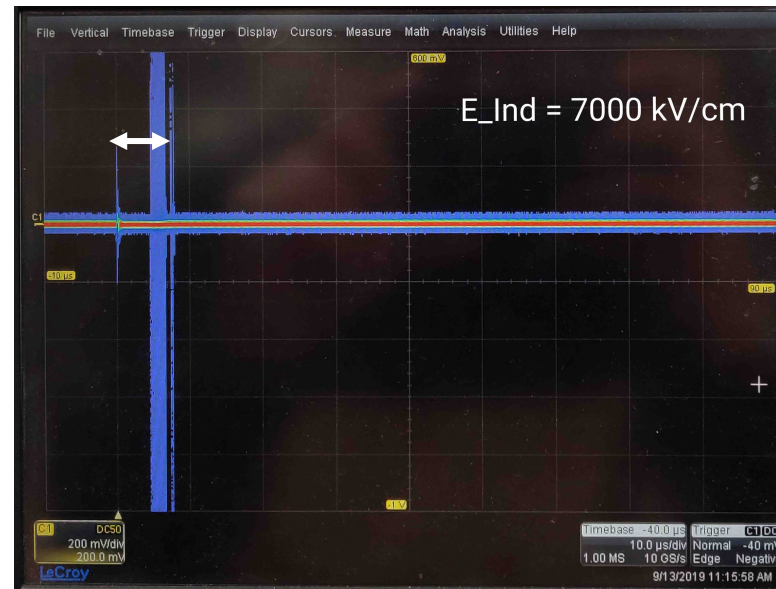
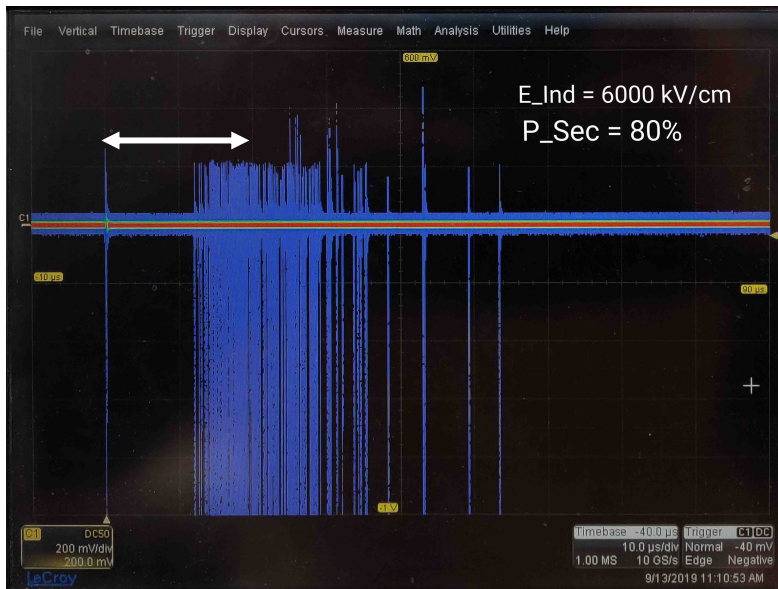
b) Secondary discharge



[A. Deisting, et al. NIM A 937 (2019) 168-180]

# Time delay

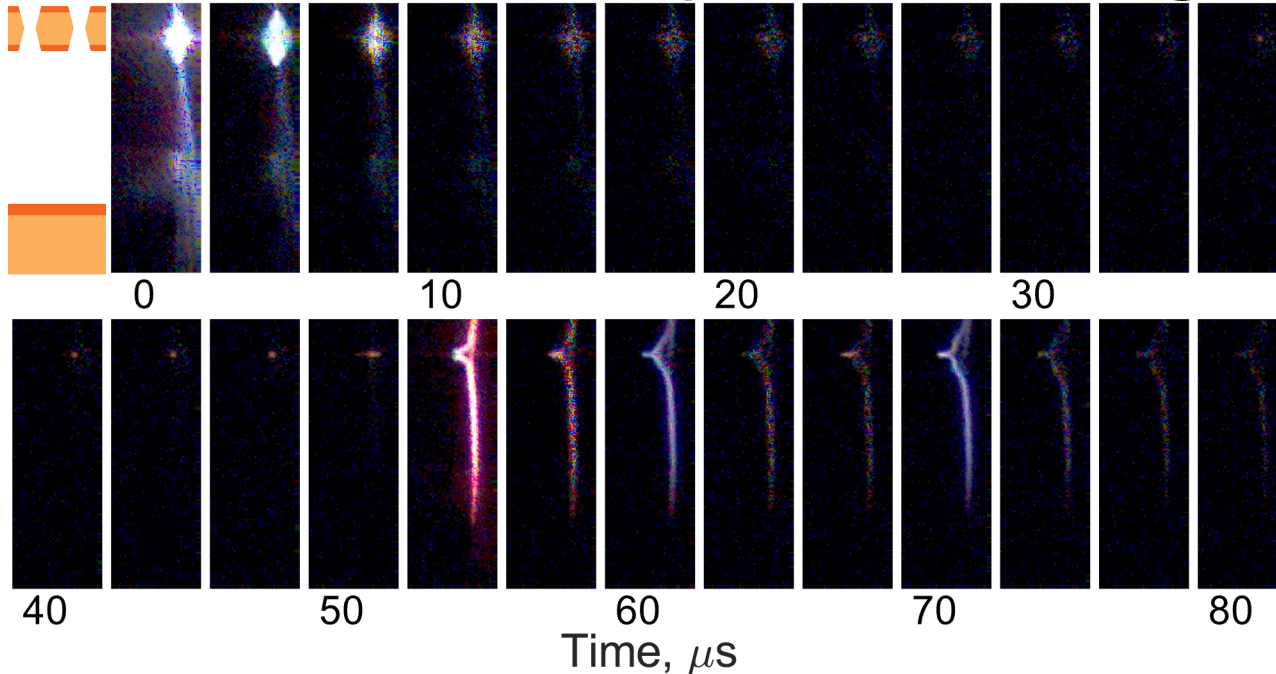
- The time difference between the primary and secondary discharge events
  - Depends on the transport properties of the used gas
  - Up to 100  $\mu\text{s}$  in Argon based gas mixtures
  - Shorter delay with increased induction field



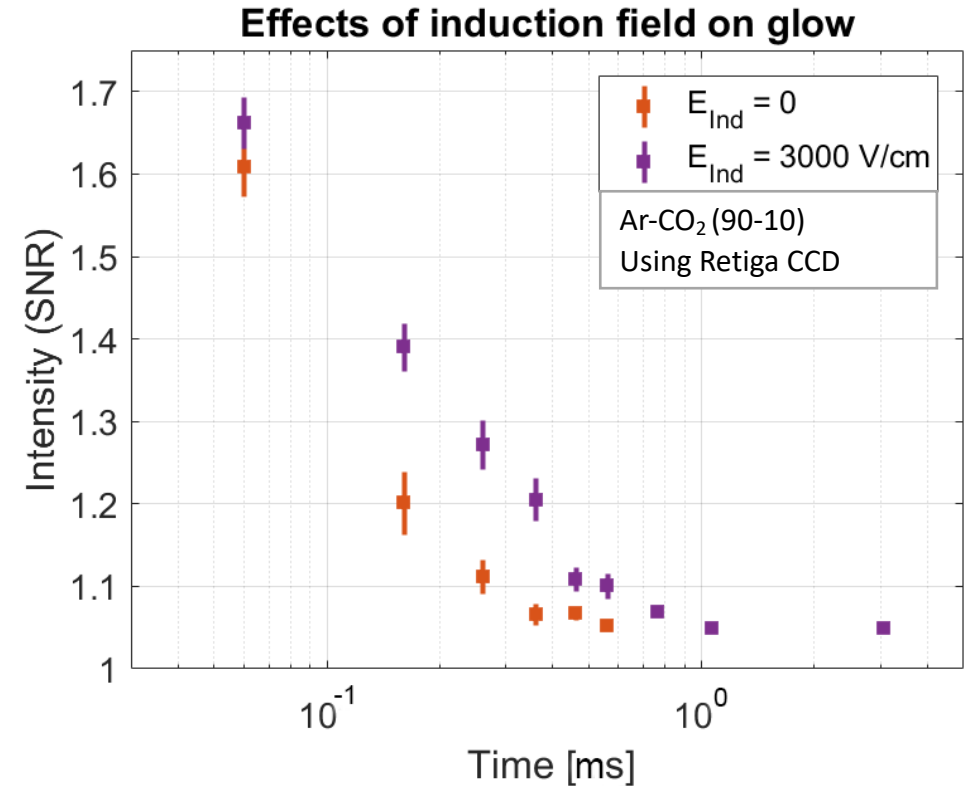
# Thermionic emission of electrons

- Increased activity around the discharged hole observed to persist with applied induction field

GEM @  $E_{ind} = 5.66 \text{ kv/cm}$ ,  $\Delta V_{GEM} = 500 \text{ V}$ ,  $R_{dec} = 0 \text{ k}\Omega$   
 PHOTRON SA-X2: 80x256, 300000 fps, S:1/583784, A:F2.8@100 mm



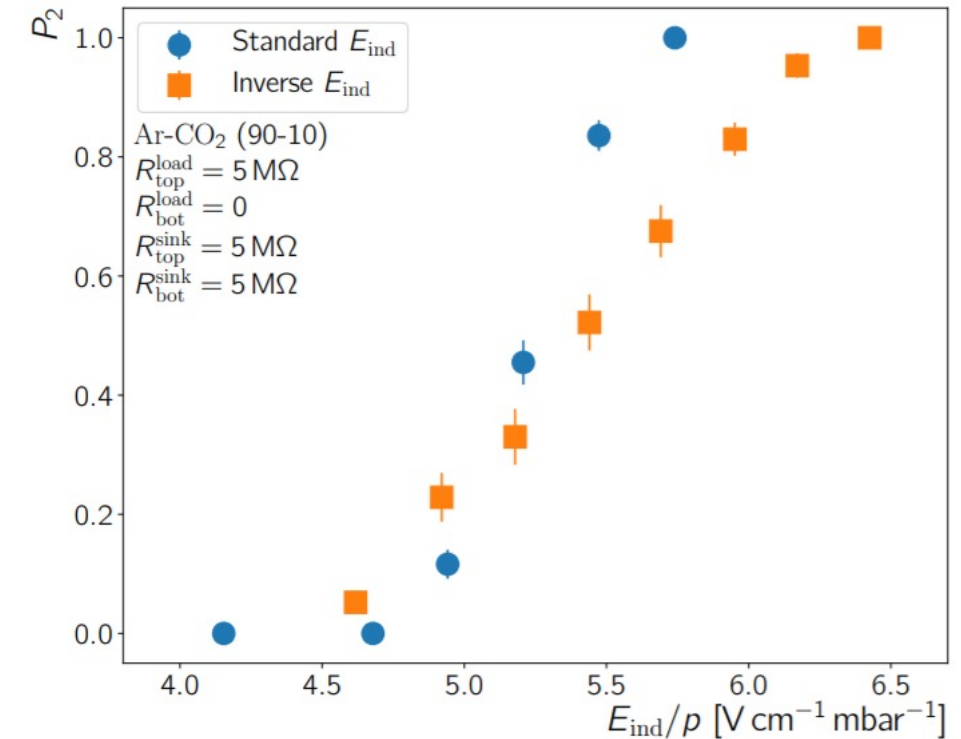
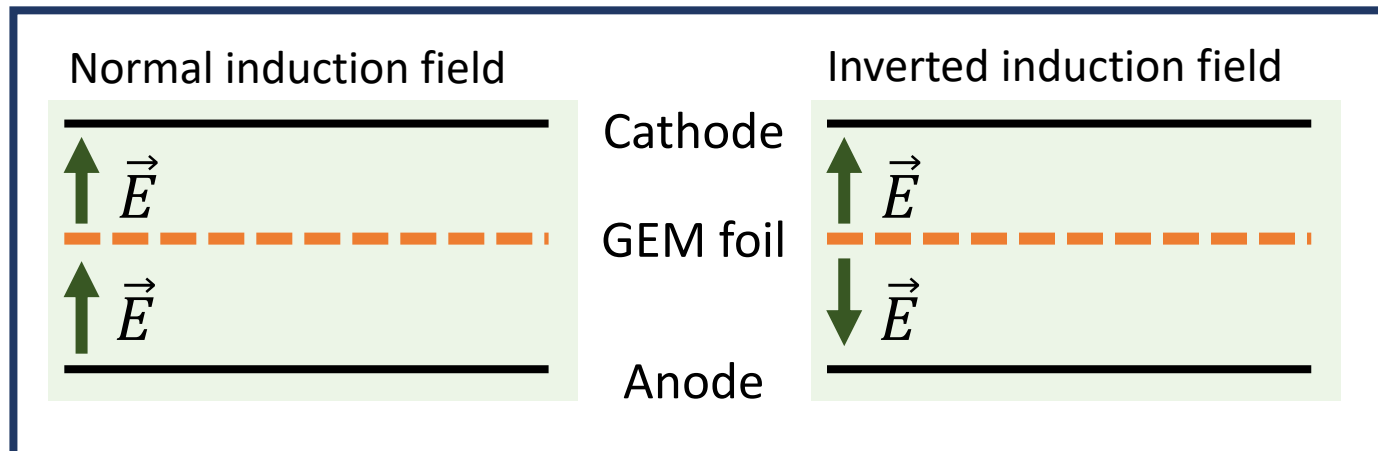
[A Utrobicic, et al. 2019 NIM A 940 262-273]



[B Ulukutlu and P Gasik 2020 J. Phys.: Conf. Ser. 1498 012035]

# Secondary discharges in inverted field

- Secondary discharges also occur even if you apply the induction field in the opposite direction
  - At similar field strengths
  - With similar time delays

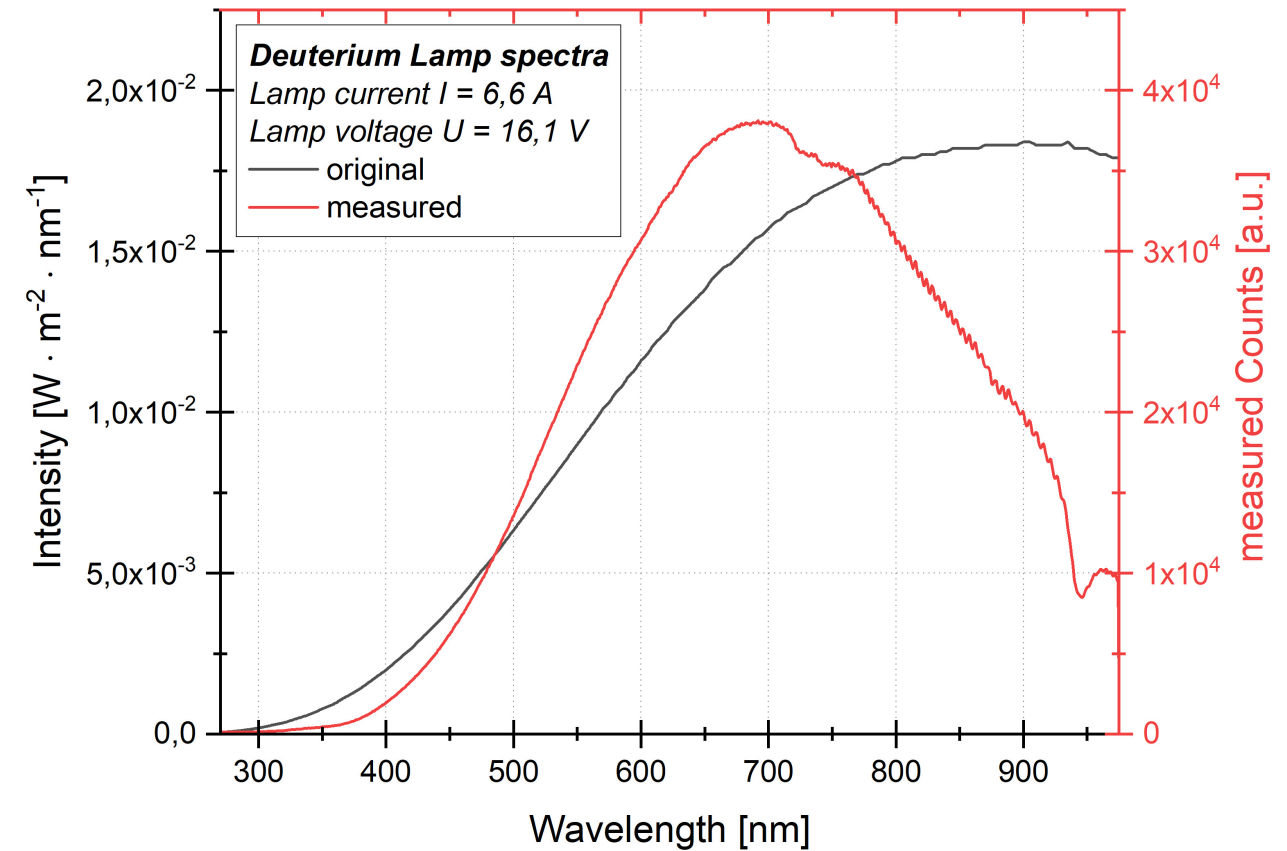
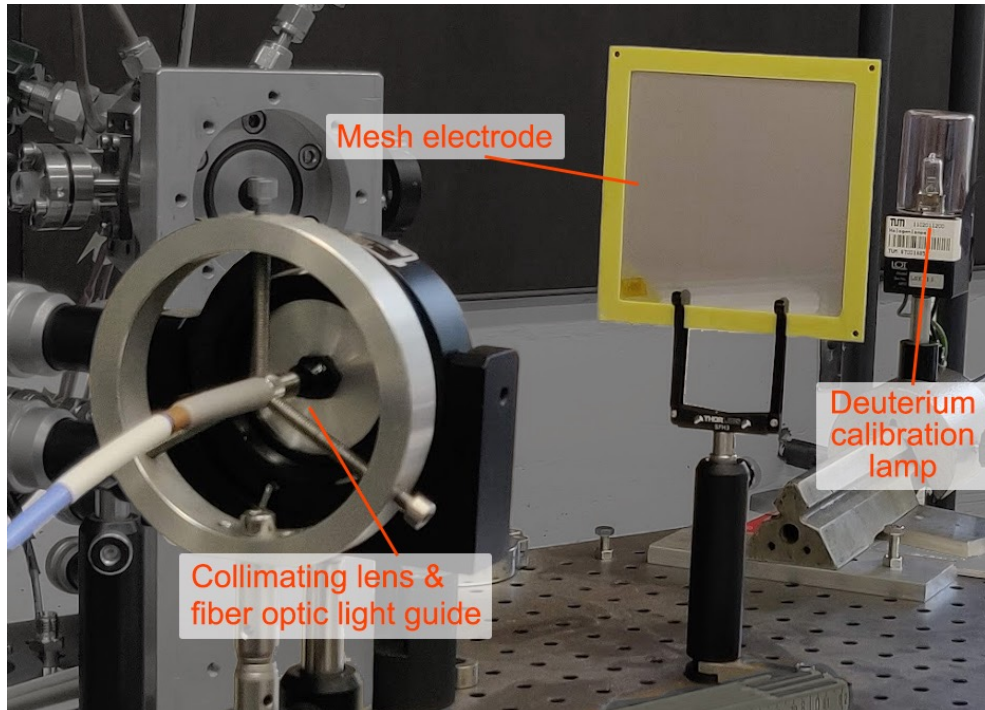


Secondary discharge probability as a function of the applied induction field strength

[A. Deisting, et al. NIM A 937 (2019) 168-180]

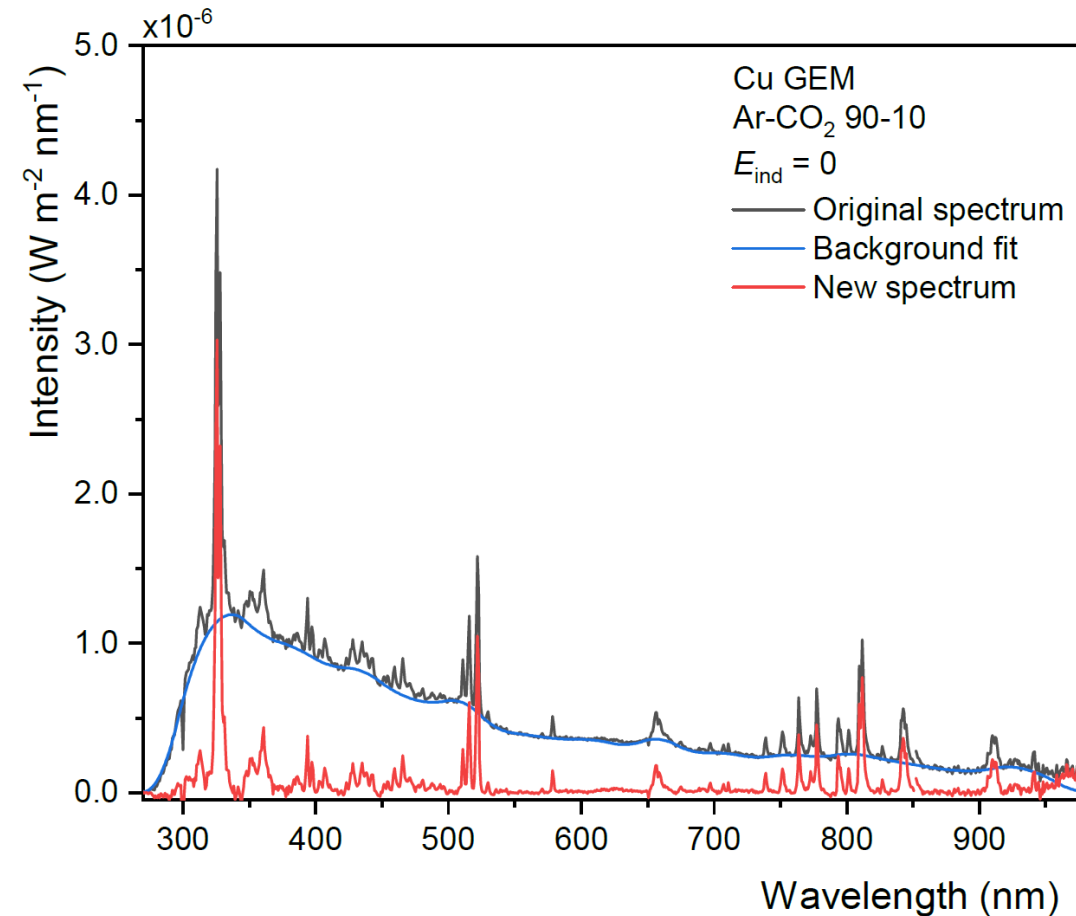
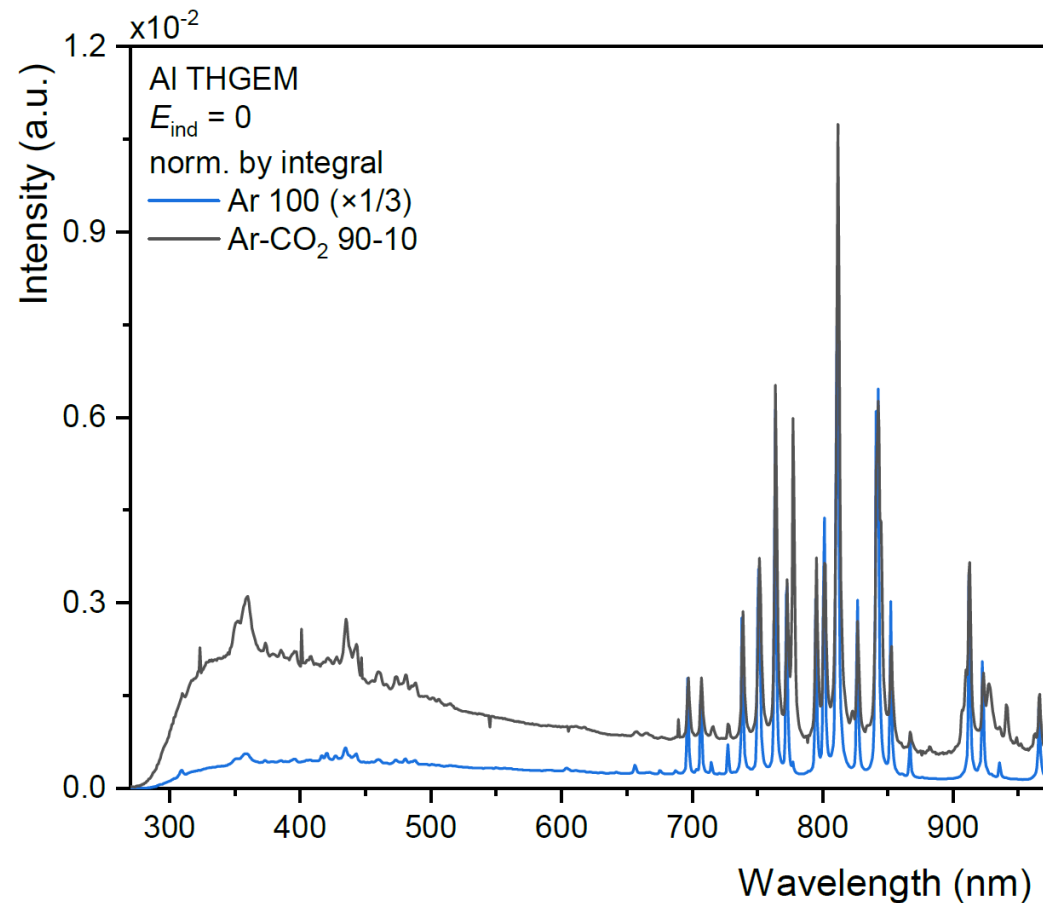
# Calibration of the spectrometer

- Using a characterized deuterium lamp for the intensity calibration



# Background subtraction on spectra

- The continuous background distribution originates from the broad emission from molecules in the plasma



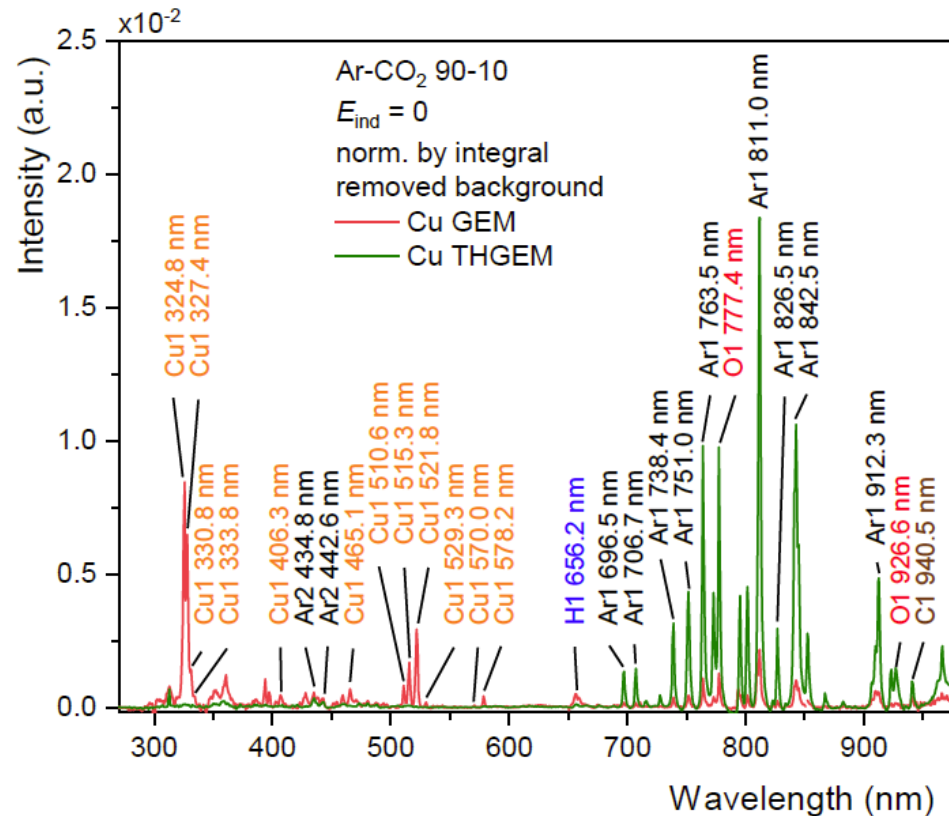


# Spectra GEM vs SH-THGEM

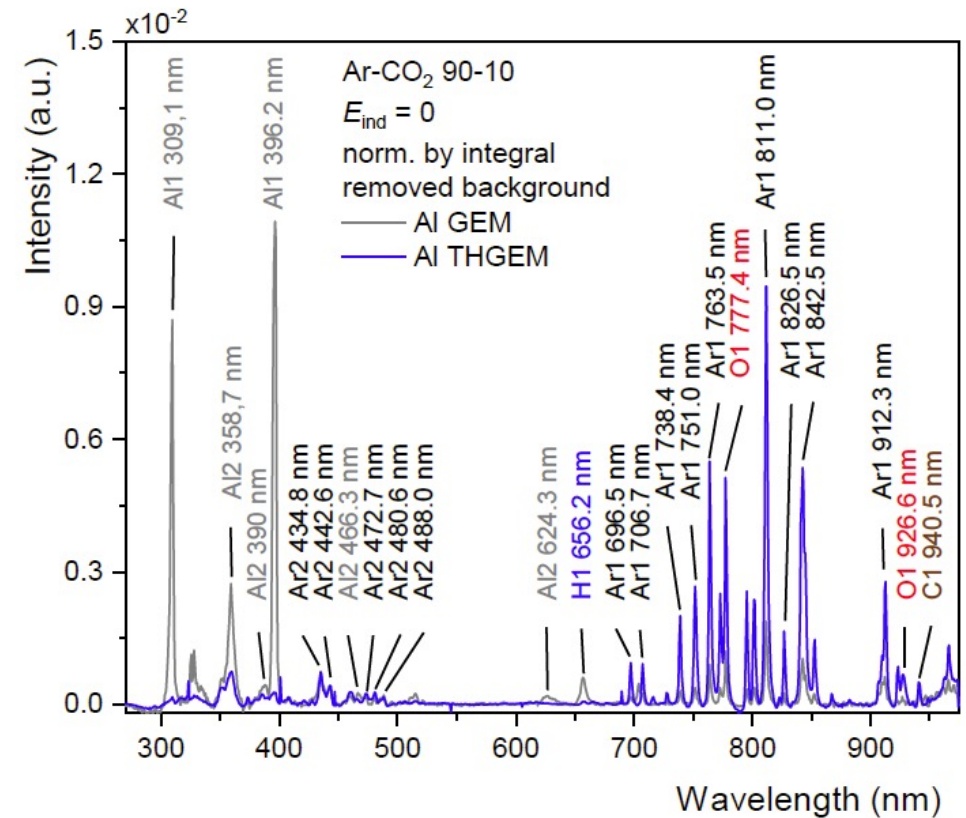
No cladding material emission lines observed with single hole THGEMs

→ None or much less vaporization of the foil material

Copper GEM vs SH-THGEM

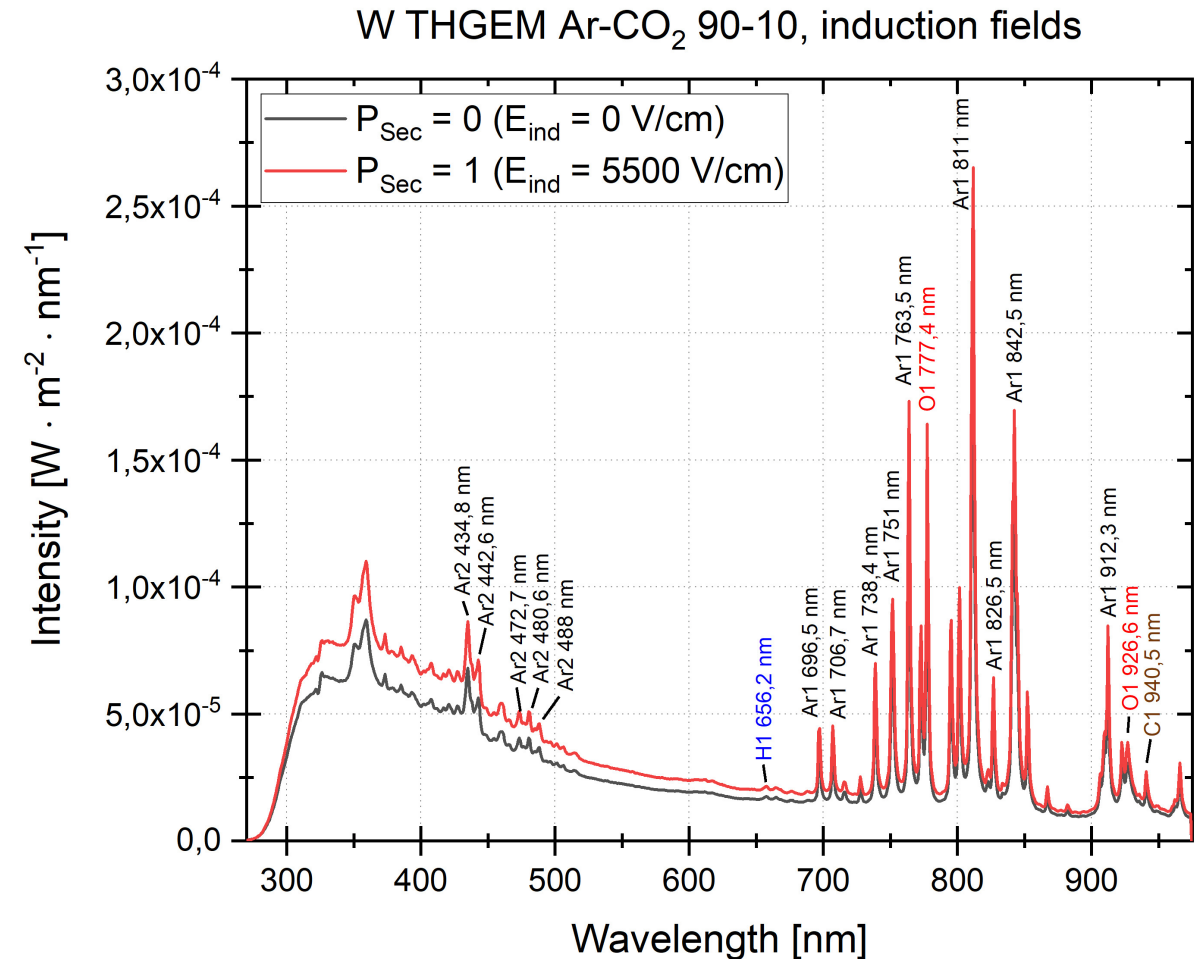


Aluminium GEM vs SH-THGEM



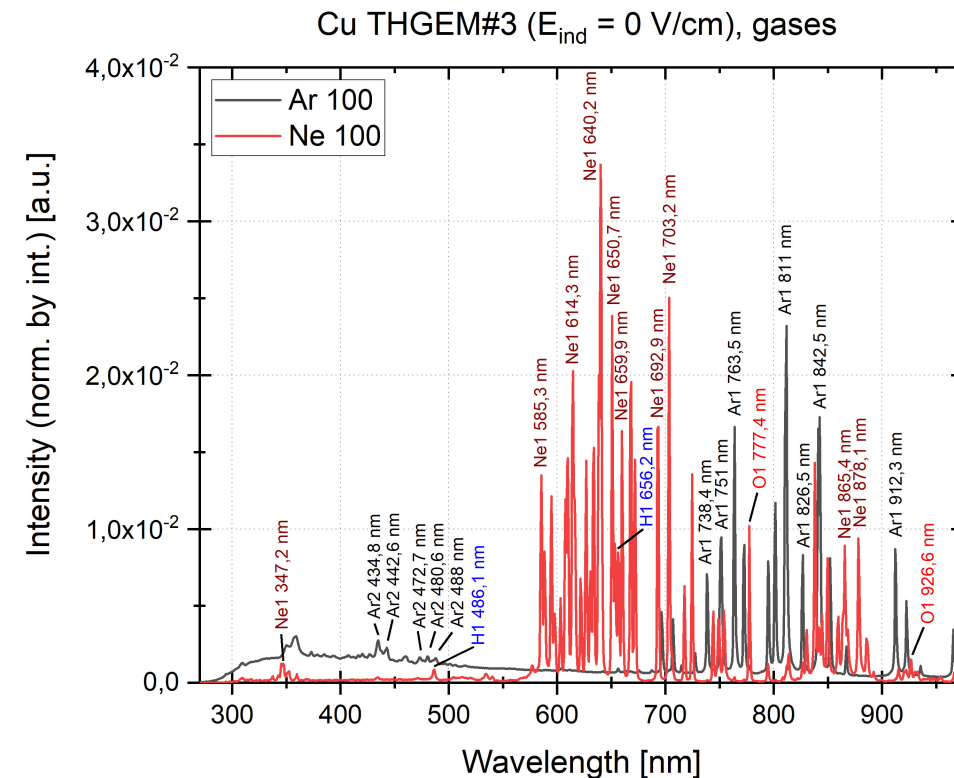
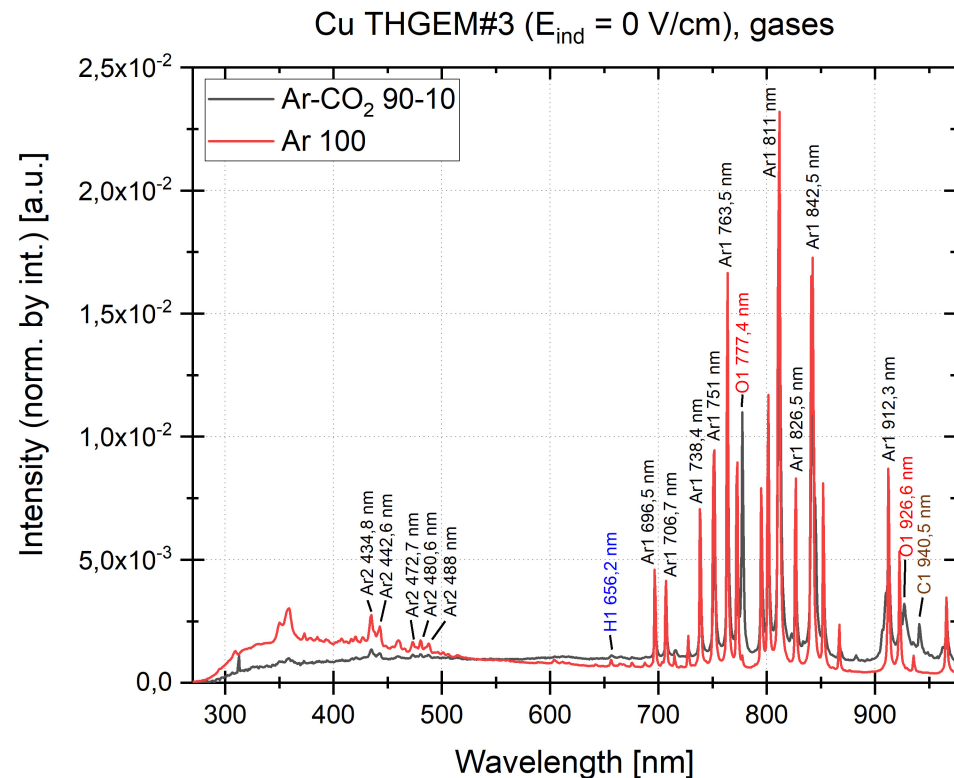
# Spectra of secondary discharges

- No major differences observed in emission spectra from primary and secondary discharges
  - Higher light emission with secondary discharges
- Slightly increased overall intensity
  - Higher light emission with secondary discharges
- The underlying physical light emission processes same for both discharge types



# Different gas mixtures

- THGEM spectra were also measured using Ar (100) and Neon (100) gas mixtures
- Corresponding gas lines can be identified



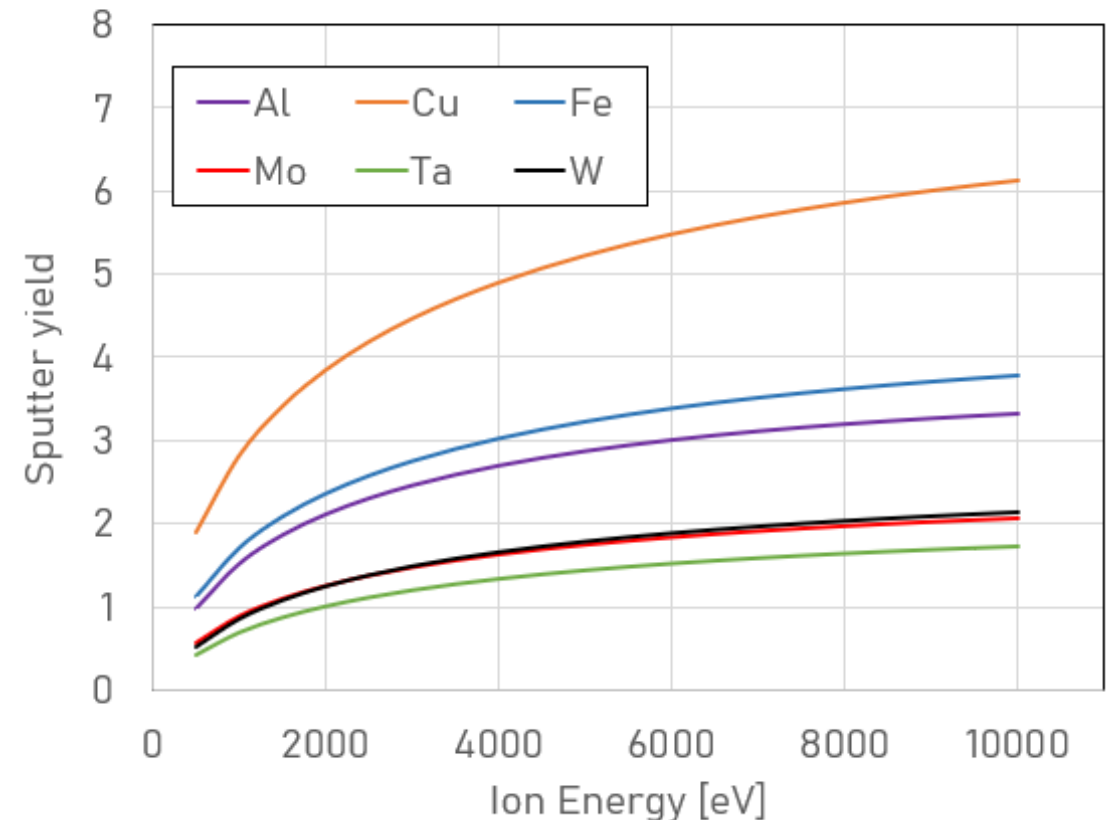
# Sputtering vs vaporization

Could sputtering be the reason we observe foil material in discharge plasma or explain the secondary discharge hierarchy?

Probably not:

- Burn marks observed mainly on bottom side of foils
  - Ions would cause sputtering on the top side
- No material lines observed with THGEMs
  - THGEM foils having thicker metal layer shouldn't decrease sputtering yield
- Sputtering properties don't scale with the observed secondary discharge stability hierarchy of the used materials

Argon sputtering properties of the used materials



[N. Matsunami, et al. in Energy Dependence of the Yields of Ion-Induced Sputtering of Monatomic Solids, IPPJ-AM-32 (Institute of Plasma Physics, Nagoya University, Japan, 1983)]